Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/670,262	YOUN, KARP-SIK	
Examiner	Art Unit	
Vietry A. Johnson	3682	

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Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
Hai Phan 347			
Rechel Dicht 347			
Ernesto Garcia 403		7/19/2005	VAJ
INventor name search		7/19/2005	VAJ
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